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Understanding [Embedded - Microprocessors](#)

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of [Embedded - Microprocessors](#)

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	PowerPC e500
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	800MHz
Co-Processors/DSP	Signal Processing; SPE
RAM Controllers	DDR, DDR2, SDRAM
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (4)
SATA	-
USB	-
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	783-BBGA, FCBGA
Supplier Device Package	783-FCBGA (29x29)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/kmpc8543hxang

- Memory prefetching of PCI read accesses
- Supports posting of processor-to-PCI and PCI-to-memory writes
- PCI 3.3-V compatible
- Selectable hardware-enforced coherency
- Serial RapidIO™ interface unit
 - Supports *RapidIO™ Interconnect Specification, Revision 1.2*
 - Both 1× and 4× LP-serial link interfaces
 - Long- and short-haul electricals with selectable pre-compensation
 - Transmission rates of 1.25, 2.5, and 3.125 Gbaud (data rates of 1.0, 2.0, and 2.5 Gbps) per lane
 - Auto detection of 1- and 4-mode operation during port initialization
 - Link initialization and synchronization
 - Large and small size transport information field support selectable at initialization time
 - 34-bit addressing
 - Up to 256 bytes data payload
 - All transaction flows and priorities
 - Atomic set/clr/inc/dec for read-modify-write operations
 - Generation of IO_READ_HOME and FLUSH with data for accessing cache-coherent data at a remote memory system
 - Receiver-controlled flow control
 - Error detection, recovery, and time-out for packets and control symbols as required by the RapidIO specification
 - Register and register bit extensions as described in part VIII (Error Management) of the RapidIO specification
 - Hardware recovery only
 - Register support is not required for software-mediated error recovery.
 - Accept-all mode of operation for fail-over support
 - Support for RapidIO error injection
 - Internal LP-serial and application interface-level loopback modes
 - Memory and PHY BIST for at-speed production test
- RapidIO-compatible message unit
 - 4 Kbytes of payload per message
 - Up to sixteen 256-byte segments per message
 - Two inbound data message structures within the inbox
 - Capable of receiving three letters at any mailbox
 - Two outbound data message structures within the outbox
 - Capable of sending three letters simultaneously
 - Single segment multicast to up to 32 devIDs
 - Chaining and direct modes in the outbox

2.1.3 Output Driver Characteristics

The following table provides information on the characteristics of the output driver strengths. The values are preliminary estimates.

Table 3. Output Drive Capability

Driver Type	Programmable Output Impedance (Ω)	Supply Voltage	Notes
Local bus interface utilities signals	25	$BV_{DD} = 3.3\text{ V}$	1
	25	$BV_{DD} = 2.5\text{ V}$	
PCI signals	45(default)	$BV_{DD} = 3.3\text{ V}$	2
	45(default)	$BV_{DD} = 2.5\text{ V}$	
DDR signal	25	$OV_{DD} = 3.3\text{ V}$	3
	45(default)		
DDR2 signal	18	$GV_{DD} = 2.5\text{ V}$	3
	36 (half strength mode)		
TSEC/10/100 signals	18	$GV_{DD} = 1.8\text{ V}$	3
	36 (half strength mode)		
TSEC/10/100 signals	45	$L/TV_{DD} = 2.5/3.3\text{ V}$	—
DUART, system control, JTAG	45	$OV_{DD} = 3.3\text{ V}$	—
I2C	150	$OV_{DD} = 3.3\text{ V}$	—

Notes:

1. The drive strength of the local bus interface is determined by the configuration of the appropriate bits in PORIMPSCR.
2. The drive strength of the PCI interface is determined by the setting of the PCI_GNT1 signal at reset.
3. The drive strength of the DDR interface in half-strength mode is at $T_j = 105^\circ\text{C}$ and at GV_{DD} (min).

2.2 Power Sequencing

The device requires its power rails to be applied in a specific sequence in order to ensure proper device operation. These requirements are as follows for power-up:

1. V_{DD} , AV_{DD-n} , BV_{DD} , LV_{DD} , OV_{DD} , SV_{DD} , TV_{DD} , XV_{DD}
2. GV_{DD}

All supplies must be at their stable values within 50 ms.

NOTE

Items on the same line have no ordering requirement with respect to one another. Items on separate lines must be ordered sequentially such that voltage rails on a previous step must reach 90% of their value before the voltage rails on the current step reach 10% of theirs.

NOTE

In order to guarantee MCKE low during power-up, the above sequencing for GV_{DD} is required. If there is no concern about any of the DDR signals being in an indeterminate state during power-up, then the sequencing for GV_{DD} is not required.

4.5 Platform to FIFO Restrictions

Note the following FIFO maximum speed restrictions based on platform speed.

For FIFO GMII mode:

$$\text{FIFO TX/RX clock frequency} \leq \text{platform clock frequency}/4.2$$

For example, if the platform frequency is 533 MHz, the FIFO TX/RX clock frequency must be no more than 127 MHz.

For FIFO encoded mode:

$$\text{FIFO TX/RX clock frequency} \leq \text{platform clock frequency}/4.2$$

For example, if the platform frequency is 533 MHz, the FIFO TX/RX clock frequency must be no more than 167 MHz.

4.6 Platform Frequency Requirements for PCI-Express and Serial RapidIO

The CCB clock frequency must be considered for proper operation of the high-speed PCI-Express and Serial RapidIO interfaces as described below.

For proper PCI Express operation, the CCB clock frequency must be greater than:

$$\frac{527 \text{ MHz} \times (\text{PCI-Express link width})}{8}$$

See *MPC8548ERM, Rev. 2, PowerQUICC III Integrated Processor Family Reference Manual*, Section 18.1.3.2, “Link Width,” for PCI Express interface width details.

For proper serial RapidIO operation, the CCB clock frequency must be greater than:

$$\frac{2 \times (0.80) \times (\text{Serial RapidIO interface frequency}) \times (\text{Serial RapidIO link width})}{64}$$

See *MPC8548ERM, Rev. 2, PowerQUICC III Integrated Processor Family Reference Manual*, Section 17.4, “1x/4x LP-Serial Signal Descriptions,” for serial RapidIO interface width and frequency details.

4.7 Other Input Clocks

For information on the input clocks of other functional blocks of the platform see the specific section of this document.

8 Enhanced Three-Speed Ethernet (eTSEC)

This section provides the AC and DC electrical characteristics for the enhanced three-speed Ethernet controller. The electrical characteristics for MDIO and MDC are specified in [Section 9, “Ethernet Management Interface Electrical Characteristics.”](#)

8.1 Enhanced Three-Speed Ethernet Controller (eTSEC) (10/100/1Gb Mbps)—GMII/MII/TBI/RGMII/RTBI/RMII Electrical Characteristics

The electrical characteristics specified here apply to all gigabit media independent interface (GMII), media independent interface (MII), ten-bit interface (TBI), reduced gigabit media independent interface (RGMII), reduced ten-bit interface (RTBI), and reduced media independent interface (RMII) signals except management data input/output (MDIO) and management data clock (MDC). The RGMII and RTBI interfaces are defined for 2.5 V, while the GMII, MII, and TBI interfaces can be operated at 3.3 or 2.5 V. The GMII, MII, or TBI interface timing is compliant with the IEEE 802.3. The RGMII and RTBI interfaces follow the *Reduced Gigabit Media-Independent Interface (RGMII) Specification Version 1.3* (12/10/2000). The RMII interface follows the *RMII Consortium RMII Specification Version 1.2* (3/20/1998). The electrical characteristics for MDIO and MDC are specified in [Section 9, “Ethernet Management Interface Electrical Characteristics.”](#)

8.1.1 eTSEC DC Electrical Characteristics

All GMII, MII, TBI, RGMII, RMII, and RTBI drivers and receivers comply with the DC parametric attributes specified in [Table 22](#) and [Table 23](#). The RGMII and RTBI signals are based on a 2.5-V CMOS interface voltage as defined by JEDEC EIA/JESD8-5.

Table 22. GMII, MII, RMII, and TBI DC Electrical Characteristics

Parameter	Symbol	Min	Max	Unit	Notes
Supply voltage 3.3 V	V_{DD} V_{DD}	3.13	3.47	V	1, 2
Output high voltage ($V_{DD}/V_{DD} = \text{min}$, $I_{OH} = -4.0 \text{ mA}$)	V_{OH}	2.40	$V_{DD}/V_{DD} + 0.3$	V	—
Output low voltage ($V_{DD}/V_{DD} = \text{min}$, $I_{OL} = 4.0 \text{ mA}$)	V_{OL}	GND	0.50	V	—
Input high voltage	V_{IH}	2.0	$V_{DD}/V_{DD} + 0.3$	V	—
Input low voltage	V_{IL}	-0.3	0.90	V	—
Input high current ($V_{IN} = V_{DD}$, $V_{IN} = V_{DD}$)	I_{IH}	—	40	μA	1, 2, 3
Input low current ($V_{IN} = \text{GND}$)	I_{IL}	-600	—	μA	—

Notes:

1. V_{DD} supports eTSECs 1 and 2.
2. V_{DD} supports eTSECs 3 and 4.
3. The symbol V_{IN} , in this case, represents the V_{IN} and V_{IN} symbols referenced in [Table 1](#) and [Table 2](#).

Figure 11 shows the MII transmit AC timing diagram.

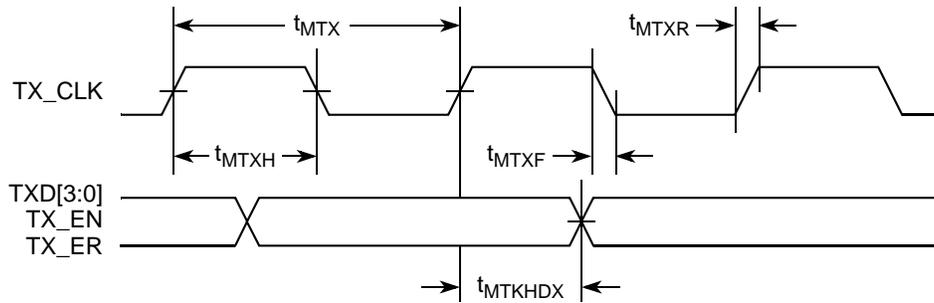


Figure 11. MII Transmit AC Timing Diagram

8.2.3.2 MII Receive AC Timing Specifications

This table provides the MII receive AC timing specifications.

Table 29. MII Receive AC Timing Specifications

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit
RX_CLK clock period 10 Mbps	t_{MRX}^2	—	400	—	ns
RX_CLK clock period 100 Mbps	t_{MRX}	—	40	—	ns
RX_CLK duty cycle	t_{MRXH}/t_{MRX}	35	—	65	%
RXD[3:0], RX_DV, RX_ER setup time to RX_CLK	t_{MRDVKH}	10.0	—	—	ns
RXD[3:0], RX_DV, RX_ER hold time to RX_CLK	t_{MRDXKH}	10.0	—	—	ns
RX_CLK clock rise (20%–80%)	t_{MRXR}^2	1.0	—	4.0	ns
RX_CLK clock fall time (80%–20%)	t_{MRXF}^2	1.0	—	4.0	ns

Notes:

- The symbols used for timing specifications follow the pattern of $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, t_{MRDVKH} symbolizes MII receive timing (MR) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{MRX} clock reference (K) going to the high (H) state or setup time. Also, t_{MRDXKL} symbolizes MII receive timing (GR) with respect to the time data input signals (D) went invalid (X) relative to the t_{MRX} clock reference (K) going to the low (L) state or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{MRX} represents the MII (M) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
- Guaranteed by design.

Figure 12 provides the AC test load for eTSEC.

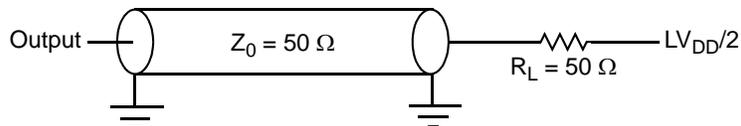


Figure 12. eTSEC AC Test Load

Figure 15 shows the TBI receive AC timing diagram.

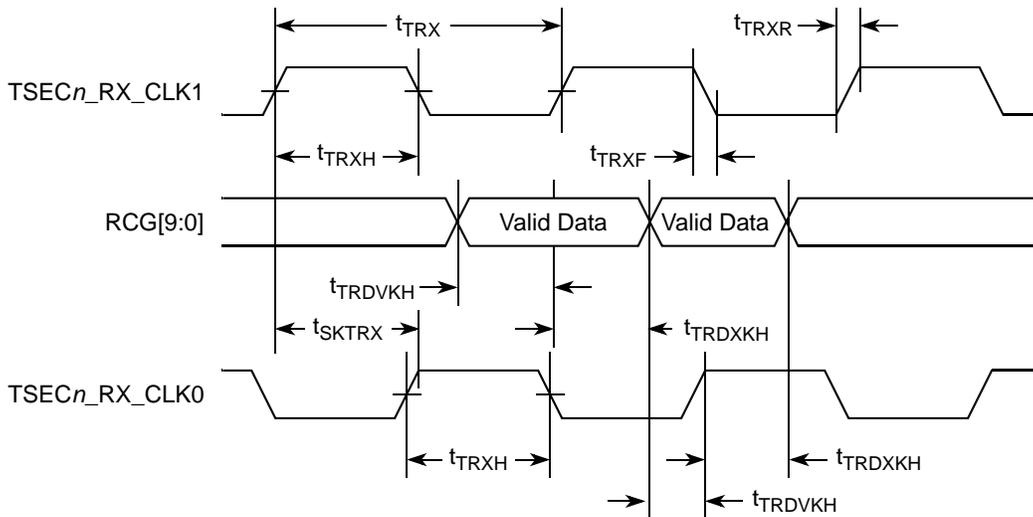


Figure 15. TBI Receive AC Timing Diagram

8.2.5 TBI Single-Clock Mode AC Specifications

When the eTSEC is configured for TBI modes, all clocks are supplied from external sources to the relevant eTSEC interface. In single-clock TBI mode, when TBICON[CLKSEL] = 1, a 125-MHz TBI receive clock is supplied on the TSECn_RX_CLK pin (no receive clock is used on TSECn_TX_CLK in this mode, whereas for the dual-clock mode this is the PMA1 receive clock). The 125-MHz transmit clock is applied on the TSEC_GTX_CLK125 pin in all TBI modes.

A summary of the single-clock TBI mode AC specifications for receive appears in Table 32.

Table 32. TBI single-clock Mode Receive AC Timing Specification

Parameter/Condition	Symbol	Min	Typ	Max	Unit
RX_CLK clock period	t _{TRRX}	7.5	8.0	8.5	ns
RX_CLK duty cycle	t _{TRRH/TRRX}	40	50	60	%
RX_CLK peak-to-peak jitter	t _{TRRJ}	—	—	250	ps
Rise time RX_CLK (20%–80%)	t _{TRRR}	—	—	1.0	ns
Fall time RX_CLK (80%–20%)	t _{TRRF}	—	—	1.0	ns
RCG[9:0] setup time to RX_CLK rising edge	t _{TRRDVKH}	2.0	—	—	ns
RCG[9:0] hold time to RX_CLK rising edge	t _{TRRDVKH}	1.0	—	—	ns

Table 41 describes the timing parameters of the local bus interface at $BV_{DD} = 2.5$ V.

Table 41. Local Bus Timing Parameters ($BV_{DD} = 2.5$ V)—PLL Enabled

Parameter	Symbol ¹	Min	Max	Unit	Notes
Local bus cycle time	t_{LBK}	7.5	12	ns	2
Local bus duty cycle	t_{LBKH}/t_{LBK}	43	57	%	—
LCLK[n] skew to LCLK[m] or LSYNC_OUT	$t_{LBKSKEW}$	—	150	ps	7, 8
Input setup to local bus clock (except $\overline{LGTA}/UPWAIT$)	$t_{LBIVKH1}$	1.9	—	ns	3, 4
$\overline{LGTA}/LUPWAIT$ input setup to local bus clock	$t_{LBIVKH2}$	1.8	—	ns	3, 4
Input hold from local bus clock (except $\overline{LGTA}/LUPWAIT$)	$t_{LBIXKH1}$	1.1	—	ns	3, 4
$\overline{LGTA}/LUPWAIT$ input hold from local bus clock	$t_{LBIXKH2}$	1.1	—	ns	3, 4
LALE output transition to LAD/LDP output transition (LATCH hold time)	t_{LBOTOT}	1.5	—	ns	6
Local bus clock to output valid (except LAD/LDP and LALE)	$t_{LBKHOV1}$	—	2.1	ns	—
Local bus clock to data valid for LAD/LDP	$t_{LBKHOV2}$	—	2.3	ns	3
Local bus clock to address valid for LAD	$t_{LBKHOV3}$	—	2.4	ns	3
Local bus clock to LALE assertion	$t_{LBKHOV4}$	—	2.4	ns	3
Output hold from local bus clock (except LAD/LDP and LALE)	$t_{LBKHOX1}$	0.8	—	ns	3
Output hold from local bus clock for LAD/LDP	$t_{LBKHOX2}$	0.8	—	ns	3
Local bus clock to output high Impedance (except LAD/LDP and LALE)	$t_{LBKHOZ1}$	—	2.6	ns	5
Local bus clock to output high impedance for LAD/LDP	$t_{LBKHOZ2}$	—	2.6	ns	5

Notes:

- The symbols used for timing specifications follow the pattern of $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, $t_{LBIXKH1}$ symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one (1). Also, t_{LBKHOX} symbolizes local bus timing (LB) for the t_{LBK} clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
- All timings are in reference to LSYNC_IN for PLL enabled and internal local bus clock for PLL bypass mode.
- All signals are measured from $BV_{DD}/2$ of the rising edge of LSYNC_IN for PLL enabled or internal local bus clock for PLL bypass mode to $0.4 \times BV_{DD}$ of the signal in question for 3.3-V signaling levels.
- Input timings are measured at the pin.
- For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
- t_{LBOTOT} is a measurement of the minimum time between the negation of LALE and any change in LAD. t_{LBOTOT} is programmed with the LBCR[AHD] parameter.
- Maximum possible clock skew between a clock LCLK[m] and a relative clock LCLK[n]. Skew measured between complementary signals at $BV_{DD}/2$.
- Guaranteed by design.

Figure 22 provides the AC test load for the local bus.

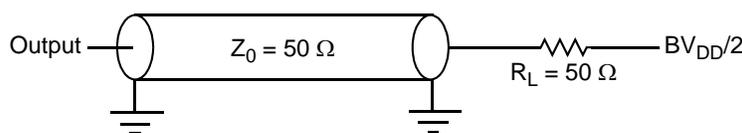


Figure 22. Local Bus AC Test Load

NOTE

PLL bypass mode is required when LBIU frequency is at or below 83 MHz. When LBIU operates above 83 MHz, LBIU PLL is recommended to be enabled.

Figure 23 through Figure 28 show the local bus signals.

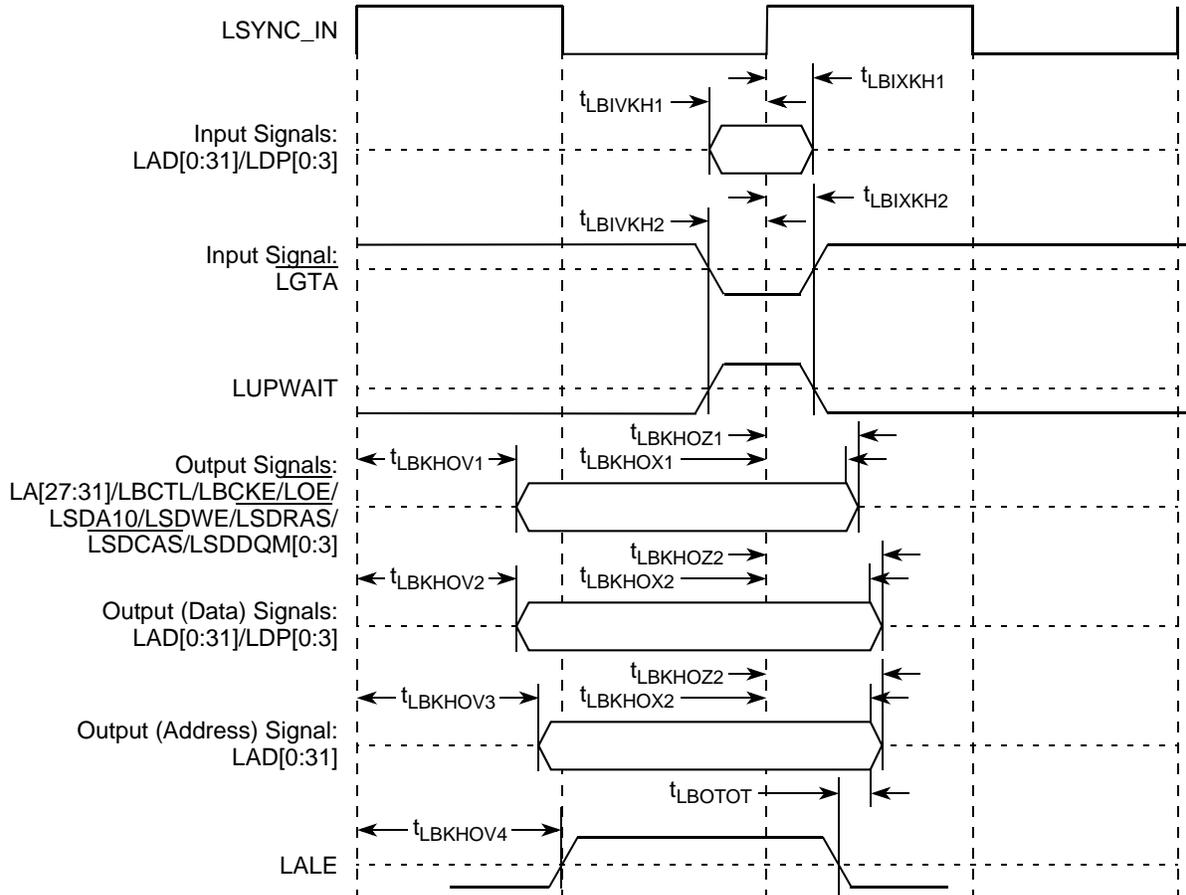


Figure 23. Local Bus Signals (PLL Enabled)

This table describes the timing parameters of the local bus interface at $V_{DD} = 3.3\text{ V}$ with PLL disabled.

Table 42. Local Bus Timing Parameters—PLL Bypassed

Parameter	Symbol ¹	Min	Max	Unit	Notes
Local bus cycle time	t_{LBK}	12	—	ns	2
Local bus duty cycle	t_{LBKH}/t_{LBK}	43	57	%	—
Internal launch/capture clock to LCLK delay	t_{LBKHT}	2.3	4.4	ns	8
Input setup to local bus clock (except $\overline{LGTA}/\overline{LUPWAIT}$)	$t_{LBIVKH1}$	6.2	—	ns	4, 5
$\overline{LGTA}/\overline{LUPWAIT}$ input setup to local bus clock	$t_{LBIVKL2}$	6.1	—	ns	4, 5
Input hold from local bus clock (except $\overline{LGTA}/\overline{LUPWAIT}$)	$t_{LBIXKH1}$	-1.8	—	ns	4, 5

Local Bus

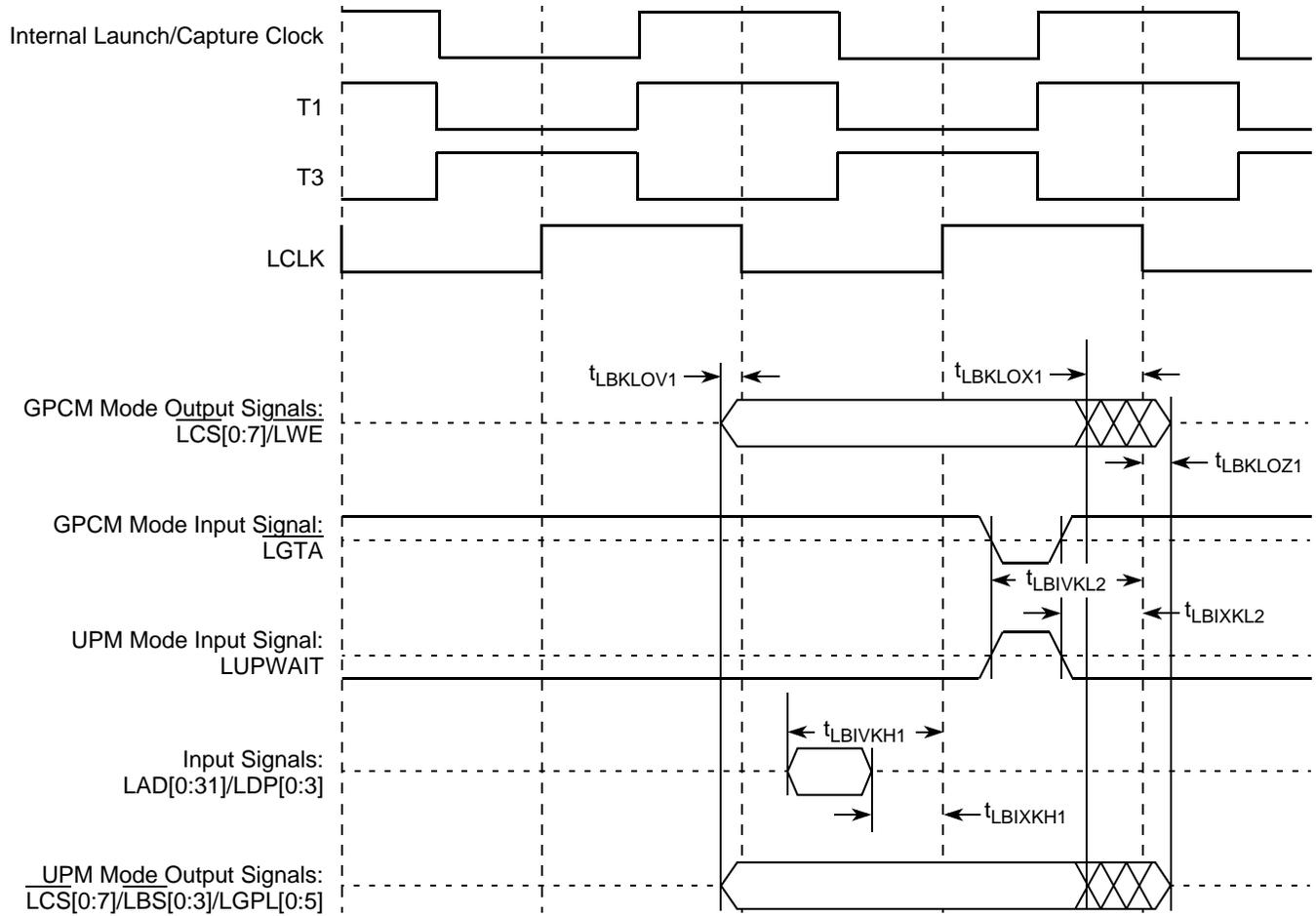


Figure 26. Local Bus Signals, GPCM/UPM Signals for LCCR[CLKDIV] = 4 (PLL Bypass Mode)

16 High-Speed Serial Interfaces (HSSI)

The device features one Serializer/Deserializer (SerDes) interface to be used for high-speed serial interconnect applications. The SerDes interface can be used for PCI Express and/or serial RapidIO data transfers.

This section describes the common portion of SerDes DC electrical specifications, which is the DC requirement for SerDes reference clocks. The SerDes data lane's transmitter and receiver reference circuits are also shown.

16.1 Signal Terms Definition

The SerDes utilizes differential signaling to transfer data across the serial link. This section defines terms used in the description and specification of differential signals.

Figure 38 shows how the signals are defined. For illustration purpose, only one SerDes lane is used for the description. The figure shows a waveform for either a transmitter output (SD_TX and $\overline{SD_TX}$) or a receiver input (SD_RX and $\overline{SD_RX}$). Each signal swings between A volts and B volts where $A > B$.

Using this waveform, the definitions are as follows. To simplify the illustration, the following definitions assume that the SerDes transmitter and receiver operate in a fully symmetrical differential signaling environment.

- **Single-ended swing**
The transmitter output signals and the receiver input signals SD_TX , $\overline{SD_TX}$, SD_RX and $\overline{SD_RX}$ each have a peak-to-peak swing of $A - B$ volts. This is also referred as each signal wire's single-ended swing.
- **Differential output voltage, V_{OD} (or differential output swing):**
The differential output voltage (or swing) of the transmitter, V_{OD} , is defined as the difference of the two complimentary output voltages: $V_{SD_TX} - V_{\overline{SD_TX}}$. The V_{OD} value can be either positive or negative.
- **Differential input voltage, V_{ID} (or differential input swing):**
The differential input voltage (or swing) of the receiver, V_{ID} , is defined as the difference of the two complimentary input voltages: $V_{SD_RX} - V_{\overline{SD_RX}}$. The V_{ID} value can be either positive or negative.
- **Differential peak voltage, V_{DIFFp}**
The peak value of the differential transmitter output signal or the differential receiver input signal is defined as differential peak voltage, $V_{DIFFp} = |A - B|$ volts.
- **Differential peak-to-peak, $V_{DIFFp-p}$**
Because the differential output signal of the transmitter and the differential input signal of the receiver each range from $A - B$ to $-(A - B)$ volts, the peak-to-peak value of the differential transmitter output signal or the differential receiver input signal is defined as differential peak-to-peak voltage, $V_{DIFFp-p} = 2 \times V_{DIFFp} = 2 \times |A - B|$ volts, which is twice of differential swing in amplitude, or twice of the differential peak. For example, the output differential peak-to-peak voltage can also be calculated as $V_{TX-DIFFp-p} = 2 \times |V_{OD}|$.
- **Common mode voltage, V_{cm}**
The common mode voltage is equal to one half of the sum of the voltages between each conductor

- The input amplitude of the differential clock must be between 400 and 1600 mV differential peak-peak (or between 200 and 800 mV differential peak). In other words, each signal wire of the differential pair must have a single-ended swing less than 800 mV and greater than 200 mV. This requirement is the same for both external DC- or AC-coupled connection.
- For external DC-coupled connection, as described in [Section 16.2.1, “SerDes Reference Clock Receiver Characteristics,”](#) the maximum average current requirements sets the requirement for average voltage (common mode voltage) to be between 100 and 400 mV. [Figure 40](#) shows the SerDes reference clock input requirement for DC-coupled connection scheme.
- For external AC-coupled connection, there is no common mode voltage requirement for the clock driver. Since the external AC-coupling capacitor blocks the DC level, the clock driver and the SerDes reference clock receiver operate in different command mode voltages. The SerDes reference clock receiver in this connection scheme has its common mode voltage set to SGND_SRDS n . Each signal wire of the differential inputs is allowed to swing below and above the command mode voltage (SGND_SRDS n). [Figure 41](#) shows the SerDes reference clock input requirement for AC-coupled connection scheme.
- Single-ended mode
 - The reference clock can also be single-ended. The SD_REF_CLK input amplitude (single-ended swing) must be between 400 and 800 mV peak-to-peak (from V_{min} to V_{max}) with SD_REF_CLK either left unconnected or tied to ground.
 - The SD_REF_CLK input average voltage must be between 200 and 400 mV. [Figure 42](#) shows the SerDes reference clock input requirement for single-ended signaling mode.
 - To meet the input amplitude requirement, the reference clock inputs might need to be DC- or AC-coupled externally. For the best noise performance, the reference of the clock could be DC- or AC-coupled into the unused phase (SD_REF_CLK) through the same source impedance as the clock input (SD_REF_CLK) in use.

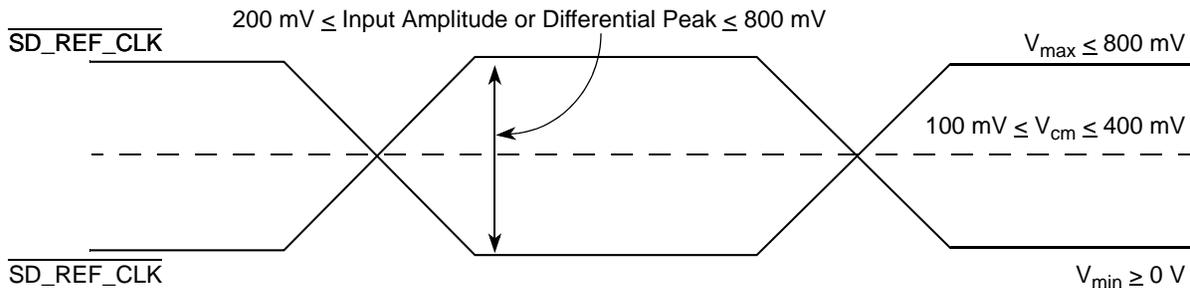


Figure 40. Differential Reference Clock Input DC Requirements (External DC-Coupled)

18 Serial RapidIO

This section describes the DC and AC electrical specifications for the RapidIO interface of the MPC8548E, for the LP-Serial physical layer. The electrical specifications cover both single- and multiple-lane links. Two transmitters (short and long run) and a single receiver are specified for each of three baud rates, 1.25, 2.50, and 3.125 GBaud.

Two transmitter specifications allow for solutions ranging from simple board-to-board interconnect to driving two connectors across a backplane. A single receiver specification is given that accepts signals from both the short- and long-run transmitter specifications.

The short-run transmitter must be used mainly for chip-to-chip connections on either the same printed-circuit board or across a single connector. This covers the case where connections are made to a mezzanine (daughter) card. The minimum swings of the short-run specification reduce the overall power used by the transceivers.

The long-run transmitter specifications use larger voltage swings that are capable of driving signals across backplanes. This allows a user to drive signals across two connectors and a backplane. The specifications allow a distance of at least 50 cm at all baud rates.

All unit intervals are specified with a tolerance of ± 100 ppm. The worst case frequency difference between any transmit and receive clock is 200 ppm.

To ensure interoperability between drivers and receivers of different vendors and technologies, AC coupling at the receiver input must be used.

18.1 DC Requirements for Serial RapidIO SD_REF_CLK and SD_REF_CLK

For more information, see [Section 16.2, “SerDes Reference Clocks.”](#)

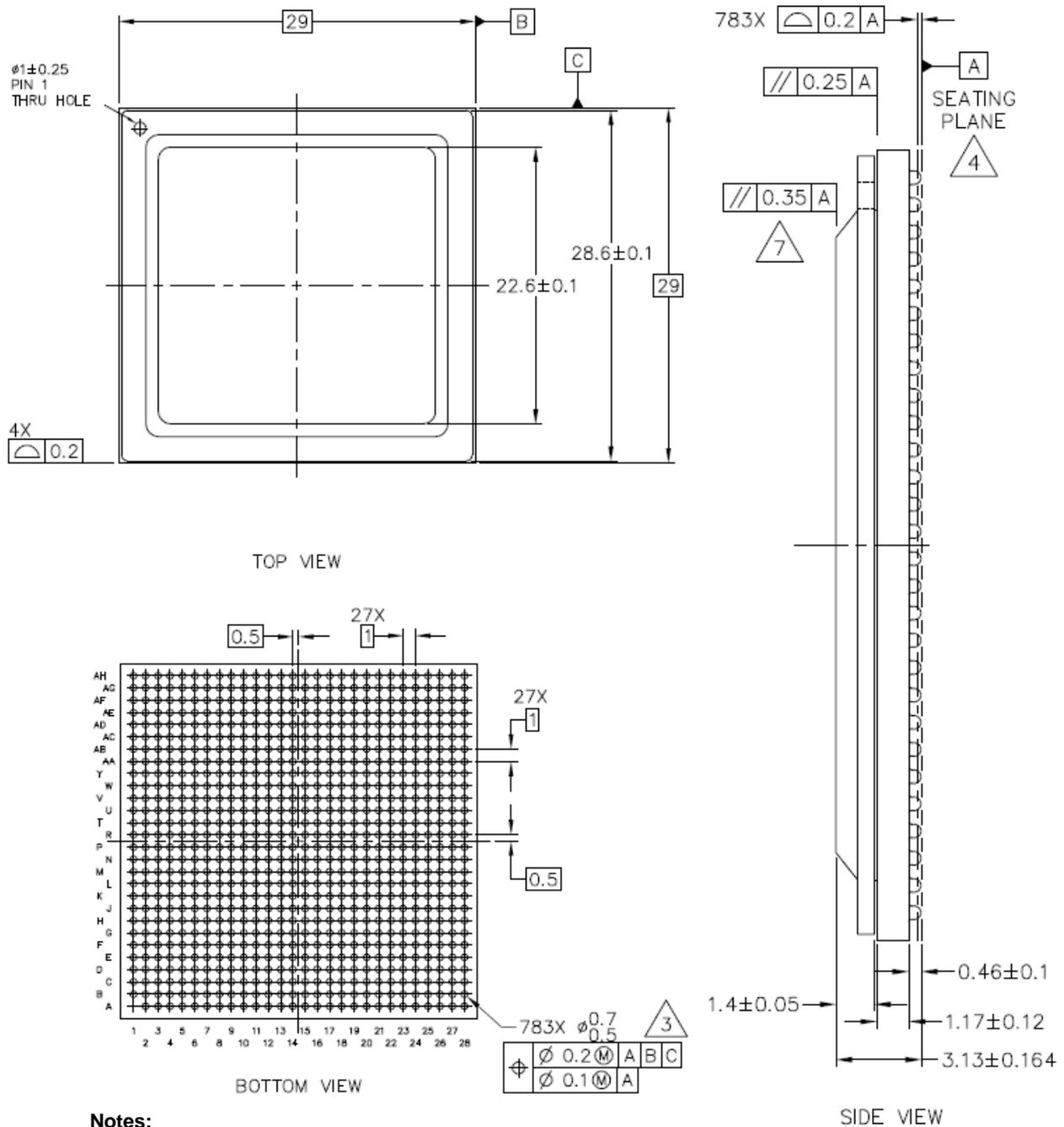
18.2 AC Requirements for Serial RapidIO SD_REF_CLK and SD_REF_CLK

[Table 58](#) lists the Serial RapidIO SD_REF_CLK and $\overline{\text{SD_REF_CLK}}$ AC requirements.

Table 58. SD_REF_CLK and $\overline{\text{SD_REF_CLK}}$ AC Requirements

Symbol	Parameter Description	Min	Typ	Max	Unit	Comments
t_{REF}	REFCLK cycle time	—	10(8)	—	ns	8 ns applies only to serial RapidIO with 125-MHz reference clock
t_{REFCJ}	REFCLK cycle-to-cycle jitter. Difference in the period of any two adjacent REFCLK cycles.	—	—	80	ps	—
t_{REFPJ}	Phase jitter. Deviation in edge location with respect to mean edge location.	-40	—	40	ps	—

Package Description



Notes:

1. All dimensions are in millimeters.
2. Dimensioning and tolerancing per ASME Y14.5M-1994.
3. Maximum solder ball diameter measured parallel to datum A.
4. Datum A, the seating plane, is determined by the spherical crowns of the solder balls.
5. Capacitors may not be present on all devices.
6. Caution must be taken not to short capacitors or exposed metal capacitor pads on package top.
7. Parallelism measurement shall exclude any effect of mark on top surface of package.
8. All dimensions are symmetric across the package center lines unless dimensioned otherwise.

Figure 56. Mechanical Dimensions and Bottom Surface Nomenclature of the FC-PBGA with Stamped Lid

Table 71. MPC8548E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
				25. These are test signals for factory use only and must be pulled up (100 Ω –1 k Ω) to OV_{DD} for normal machine operation.
				26. Independent supplies derived from board V_{DD} .
				27. Recommend a pull-up resistor (~1 k Ω) be placed on this pin to OV_{DD} .
				29. The following pins must NOT be pulled down during power-on reset: TSEC3_TXD[3], TSEC4_TXD3/TSEC3_TXD7, HRESET_REQ, TRIG_OUT/READY/QUIESCE, MSRCID[2:4], ASLEEP.
				30. This pin requires an external 4.7-k Ω pull-down resistor to prevent PHY from seeing a valid transmit enable before it is actively driven.
				31. This pin is only an output in eTSEC3 FIFO mode when used as Rx flow control.
				32. These pins must be connected to XV_{DD} .
				33. TSEC2_TXD1, TSEC2_TX_ER are multiplexed as <code>cfg_dram_type[0:1]</code> . They must be valid at power-up, even before $\overline{\text{HRESET}}$ assertion.
				34. These pins must be pulled to ground through a 300- Ω ($\pm 10\%$) resistor.
				35. When a PCI block is disabled, either the POR config pin that selects between internal and external arbiter must be pulled down to select external arbiter if there is any other PCI device connected on the PCI bus, or leave the $PCIn_AD$ pins as 'no connect' or terminated through 2–10 k Ω pull-up resistors with the default of internal arbiter if the $PCIn_AD$ pins are not connected to any other PCI device. The PCI block drives the $PCIn_AD$ pins if it is configured to be the PCI arbiter—through POR config pins—irrespective of whether it is disabled via the DEVDISR register or not. It may cause contention if there is any other PCI device connected on the bus.
				36. MDIC0 is grounded through an 18.2- Ω precision 1% resistor and MDIC1 is connected to GV_{DD} through an 18.2- Ω precision 1% resistor. These pins are used for automatic calibration of the DDR IOs.
				38. These pins must be left floating.
				39. If PCI1 or PCI2 is configured as PCI asynchronous mode, a valid clock must be provided on pin PCI1_CLK or PCI2_CLK. Otherwise the processor will not boot up.
				40. These pins must be connected to GND.
				101. This pin requires an external 4.7-k Ω resistor to GND.
				102. For Rev. 2.x silicon, $\overline{\text{DMA_DACK}}[0:1]$ must be 0b11 during POR configuration; for rev. 1.x silicon, the pin values during POR configuration are don't care.
				103. If these pins are not used as $GPINn$ (general-purpose input), they must be pulled low (to GND) or high (to LV_{DD}) through 2–10 k Ω resistors.
				104. These must be pulled low to GND through 2–10 k Ω resistors if they are not used.
				105. These must be pulled low or high to LV_{DD} through 2–10 k Ω resistors if they are not used.
				106. For rev. 2.x silicon, $\overline{\text{DMA_DACK}}[0:1]$ must be 0b10 during POR configuration; for rev. 1.x silicon, the pin values during POR configuration are don't care.
				107. For rev. 2.x silicon, $\overline{\text{DMA_DACK}}[0:1]$ must be 0b01 during POR configuration; for rev. 1.x silicon, the pin values during POR configuration are don't care.
				108. For rev. 2.x silicon, $\overline{\text{DMA_DACK}}[0:1]$ must be 0b11 during POR configuration; for rev. 1.x silicon, the pin values during POR configuration are don't care.
				109. This is a test signal for factory use only and must be pulled down (100 Ω – 1 k Ω) to GND for normal machine operation.
				110. These pins must be pulled high to OV_{DD} through 2–10 k Ω resistors.
				111. If these pins are not used as $GPINn$ (general-purpose input), they must be pulled low (to GND) or high (to OV_{DD}) through 2–10 k Ω resistors.
				112. This pin must not be pulled down during POR configuration.
				113. These should be pulled low or high to OV_{DD} through 2–10 k Ω resistors.

Table 72. MPC8547E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
Reserved	AE26	—	—	2
cfg_pci1_clk	AG24	I	OV _{DD}	5
Reserved	AF25	—	—	101
Reserved	AE25	—	—	2
Reserved	AG25	—	—	2
Reserved	AD24	—	—	2
Reserved	AF24	—	—	2
Reserved	AD27	—	—	2
Reserved	AD28, AE27, W17, AF26	—	—	2
Reserved	AH25	—	—	2
DDR SDRAM Memory Interface				
MDQ[0:63]	L18, J18, K14, L13, L19, M18, L15, L14, A17, B17, A13, B12, C18, B18, B13, A12, H18, F18, J14, F15, K19, J19, H16, K15, D17, G16, K13, D14, D18, F17, F14, E14, A7, A6, D5, A4, C8, D7, B5, B4, A2, B1, D1, E4, A3, B2, D2, E3, F3, G4, J5, K5, F6, G5, J6, K4, J1, K2, M5, M3, J3, J2, L1, M6	I/O	GV _{DD}	—
MECC[0:7]	H13, F13, F11, C11, J13, G13, D12, M12	I/O	GV _{DD}	—
MDM[0:8]	M17, C16, K17, E16, B6, C4, H4, K1, E13	O	GV _{DD}	—
MDQS[0:8]	M15, A16, G17, G14, A5, D3, H1, L2, C13	I/O	GV _{DD}	—
$\overline{\text{MDQS}}$ [0:8]	L17, B16, J16, H14, C6, C2, H3, L4, D13	I/O	GV _{DD}	—
MA[0:15]	A8, F9, D9, B9, A9, L10, M10, H10, K10, G10, B8, E10, B10, G6, A10, L11	O	GV _{DD}	—
MBA[0:2]	F7, J7, M11	O	GV _{DD}	—
$\overline{\text{MWE}}$	E7	O	GV _{DD}	—
$\overline{\text{MCAS}}$	H7	O	GV _{DD}	—
$\overline{\text{MRAS}}$	L8	O	GV _{DD}	—
MCKE[0:3]	F10, C10, J11, H11	O	GV _{DD}	11
$\overline{\text{MCS}}$ [0:3]	K8, J8, G8, F8	O	GV _{DD}	—
MCK[0:5]	H9, B15, G2, M9, A14, F1	O	GV _{DD}	—
$\overline{\text{MCK}}$ [0:5]	J9, A15, G1, L9, B14, F2	O	GV _{DD}	—
MODT[0:3]	E6, K6, L7, M7	O	GV _{DD}	—
MDIC[0:1]	A19, B19	I/O	GV _{DD}	36

Table 72. MPC8547E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
TSEC2_TX_ER	R10	O	LV _{DD}	5, 9, 33
Three-Speed Ethernet Controller (Gigabit Ethernet 3)				
TSEC3_TXD[3:0]	V8, W10, Y10, W7	O	TV _{DD}	5, 9, 29
TSEC3_RXD[3:0]	Y1, W3, W5, W4	I	TV _{DD}	—
TSEC3_GTX_CLK	W8	O	TV _{DD}	—
TSEC3_RX_CLK	W2	I	TV _{DD}	—
TSEC3_RX_DV	W1	I	TV _{DD}	—
TSEC3_RX_ER	Y2	I	TV _{DD}	—
TSEC3_TX_CLK	V10	I	TV _{DD}	—
TSEC3_TX_EN	V9	O	TV _{DD}	30
Three-Speed Ethernet Controller (Gigabit Ethernet 4)				
TSEC4_TXD[3:0]/TSEC3_TXD[7:4]	AB8, Y7, AA7, Y8	O	TV _{DD}	1, 5, 9, 29
TSEC4_RXD[3:0]/TSEC3_RXD[7:4]	AA1, Y3, AA2, AA4	I	TV _{DD}	1
TSEC4_GTX_CLK	AA5	O	TV _{DD}	—
TSEC4_RX_CLK/TSEC3_COL	Y5	I	TV _{DD}	1
TSEC4_RX_DV/TSEC3_CRS	AA3	I/O	TV _{DD}	1, 31
TSEC4_TX_EN/TSEC3_TX_ER	AB6	O	TV _{DD}	1, 30
DUART				
$\overline{\text{UART_CTS}}[0:1]$	AB3, AC5	I	OV _{DD}	—
$\overline{\text{UART_RTS}}[0:1]$	AC6, AD7	O	OV _{DD}	—
UART_SIN[0:1]	AB5, AC7	I	OV _{DD}	—
UART_SOUT[0:1]	AB7, AD8	O	OV _{DD}	—
I²C Interface				
IIC1_SCL	AG22	I/O	OV _{DD}	4, 27
IIC1_SDA	AG21	I/O	OV _{DD}	4, 27
IIC2_SCL	AG15	I/O	OV _{DD}	4, 27
IIC2_SDA	AG14	I/O	OV _{DD}	4, 27
SerDes				
SD_RX[0:3]	M28, N26, P28, R26	I	XV _{DD}	—
$\overline{\text{SD_RX}}[0:3]$	M27, N25, P27, R25	I	XV _{DD}	—
SD_TX[0:3]	M22, N20, P22, R20	O	XV _{DD}	—
$\overline{\text{SD_TX}}[0:3]$	M23, N21, P23, R21	O	XV _{DD}	—
Reserved	W26, Y28, AA26, AB28	—	—	40
Reserved	W25, Y27, AA25, AB27	—	—	40

Table 73. MPC8545E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
$\overline{\text{PCI1_FRAME}}$	AE11	I/O	OV_{DD}	2
PCI1_IDSEL	AG9	I	OV_{DD}	—
$\overline{\text{PCI1_REQ64/PCI2_FRAME}}$	AF14	I/O	OV_{DD}	2, 5, 10
$\overline{\text{PCI1_ACK64/PCI2_DEVSEL}}$	V15	I/O	OV_{DD}	2
PCI2_CLK	AE28	I	OV_{DD}	39
$\overline{\text{PCI2_IRDY}}$	AD26	I/O	OV_{DD}	2
$\overline{\text{PCI2_PERR}}$	AD25	I/O	OV_{DD}	2
$\overline{\text{PCI2_GNT}}[4:1]$	AE26, AG24, AF25, AE25	O	OV_{DD}	5, 9, 35
$\overline{\text{PCI2_GNT0}}$	AG25	I/O	OV_{DD}	—
$\overline{\text{PCI2_SERR}}$	AD24	I/O	OV_{DD}	2,4
$\overline{\text{PCI2_STOP}}$	AF24	I/O	OV_{DD}	2
$\overline{\text{PCI2_TRDY}}$	AD27	I/O	OV_{DD}	2
$\overline{\text{PCI2_REQ}}[4:1]$	AD28, AE27, W17, AF26	I	OV_{DD}	—
$\overline{\text{PCI2_REQ0}}$	AH25	I/O	OV_{DD}	—
DDR SDRAM Memory Interface				
MDQ[0:63]	L18, J18, K14, L13, L19, M18, L15, L14, A17, B17, A13, B12, C18, B18, B13, A12, H18, F18, J14, F15, K19, J19, H16, K15, D17, G16, K13, D14, D18, F17, F14, E14, A7, A6, D5, A4, C8, D7, B5, B4, A2, B1, D1, E4, A3, B2, D2, E3, F3, G4, J5, K5, F6, G5, J6, K4, J1, K2, M5, M3, J3, J2, L1, M6	I/O	GV_{DD}	—
MECC[0:7]	H13, F13, F11, C11, J13, G13, D12, M12	I/O	GV_{DD}	—
MDM[0:8]	M17, C16, K17, E16, B6, C4, H4, K1, E13	O	GV_{DD}	—
MDQS[0:8]	M15, A16, G17, G14, A5, D3, H1, L2, C13	I/O	GV_{DD}	—
$\overline{\text{MDQS}}[0:8]$	L17, B16, J16, H14, C6, C2, H3, L4, D13	I/O	GV_{DD}	—
MA[0:15]	A8, F9, D9, B9, A9, L10, M10, H10, K10, G10, B8, E10, B10, G6, A10, L11	O	GV_{DD}	—
MBA[0:2]	F7, J7, M11	O	GV_{DD}	—
$\overline{\text{MWE}}$	E7	O	GV_{DD}	—
$\overline{\text{MCAS}}$	H7	O	GV_{DD}	—
$\overline{\text{MRAS}}$	L8	O	GV_{DD}	—
MCKE[0:3]	F10, C10, J11, H11	O	GV_{DD}	11
$\overline{\text{MCS}}[0:3]$	K8, J8, G8, F8	O	GV_{DD}	—
MCK[0:5]	H9, B15, G2, M9, A14, F1	O	GV_{DD}	—
$\overline{\text{MCK}}[0:5]$	J9, A15, G1, L9, B14, F2	O	GV_{DD}	—
MODT[0:3]	E6, K6, L7, M7	O	GV_{DD}	—

- First, the board must have at least 10×10 -nF SMT ceramic chip capacitors as close as possible to the supply balls of the device. Where the board has blind vias, these capacitors must be placed directly below the chip supply and ground connections. Where the board does not have blind vias, these capacitors must be placed in a ring around the device as close to the supply and ground connections as possible.
- Second, there must be a 1- μ F ceramic chip capacitor from each SerDes supply (SV_{DD} and XV_{DD}) to the board ground plane on each side of the device. This must be done for all SerDes supplies.
- Third, between the device and any SerDes voltage regulator there must be a 10- μ F, low equivalent series resistance (ESR) SMT tantalum chip capacitor and a 100- μ F, low ESR SMT tantalum chip capacitor. This must be done for all SerDes supplies.

22.5 Connection Recommendations

To ensure reliable operation, it is highly recommended to connect unused inputs to an appropriate signal level. All unused active low inputs must be tied to V_{DD} , TV_{DD} , BV_{DD} , OV_{DD} , GV_{DD} , and LV_{DD} , as required. All unused active high inputs must be connected to GND. All NC (no-connect) signals must remain unconnected. Power and ground connections must be made to all external V_{DD} , TV_{DD} , BV_{DD} , OV_{DD} , GV_{DD} , LV_{DD} , and GND pins of the device.

22.6 Pull-Up and Pull-Down Resistor Requirements

The device requires weak pull-up resistors (2–10 k Ω is recommended) on open drain type pins including I²C pins and PIC (interrupt) pins.

Correct operation of the JTAG interface requires configuration of a group of system control pins as demonstrated in Figure 63. Care must be taken to ensure that these pins are maintained at a valid deasserted state under normal operating conditions as most have asynchronous behavior and spurious assertion gives unpredictable results.

The following pins must not be pulled down during power-on reset: $TSEC3_TXD[3]$, $\overline{HRESET_REQ}$, $TRIG_OUT/READY/QUIESCENCE$, $MSRCID[2:4]$, $ASLEEP$. The $\overline{DMA_DACK}[0:1]$, and $TEST_SEL/TEST_SEL$ pins must be set to a proper state during POR configuration. See the pinlist table of the individual device for more details

See the PCI 2.2 specification for all pull ups required for PCI.

22.7 Output Buffer DC Impedance

The device drivers are characterized over process, voltage, and temperature. For all buses, the driver is a push-pull single-ended driver type (open drain for I²C).

To measure Z_0 for the single-ended drivers, an external resistor is connected from the chip pad to OV_{DD} or GND. Then, the value of each resistor is varied until the pad voltage is $OV_{DD}/2$ (see Figure 61). The output impedance is the average of two components, the resistances of the pull-up and pull-down devices. When data is held high, SW1 is closed (SW2 is open) and R_P is trimmed until the voltage at the pad equals $OV_{DD}/2$. R_P then becomes the resistance of the pull-up devices. R_P and R_N are designed to be close to each other in value. Then, $Z_0 = (R_P + R_N)/2$.

The platform PLL ratio and e500 PLL ratio configuration pins are not equipped with these default pull-up devices.

22.9 JTAG Configuration Signals

Correct operation of the JTAG interface requires configuration of a group of system control pins as demonstrated in [Figure 63](#). Care must be taken to ensure that these pins are maintained at a valid deasserted state under normal operating conditions as most have asynchronous behavior and spurious assertion gives unpredictable results.

Boundary-scan testing is enabled through the JTAG interface signals. The $\overline{\text{TRST}}$ signal is optional in the IEEE 1149.1 specification, but it is provided on all processors built on Power Architecture technology. The device requires $\overline{\text{TRST}}$ to be asserted during power-on reset flow to ensure that the JTAG boundary logic does not interfere with normal chip operation. While the TAP controller can be forced to the reset state using only the TCK and TMS signals, generally systems assert $\overline{\text{TRST}}$ during the power-on reset flow. Simply tying $\overline{\text{TRST}}$ to $\overline{\text{HRESET}}$ is not practical because the JTAG interface is also used for accessing the common on-chip processor (COP), which implements the debug interface to the chip.

The COP function of these processors allow a remote computer system (typically, a PC with dedicated hardware and debugging software) to access and control the internal operations of the processor. The COP interface connects primarily through the JTAG port of the processor, with some additional status monitoring signals. The COP port requires the ability to independently assert $\overline{\text{HRESET}}$ or $\overline{\text{TRST}}$ in order to fully control the processor. If the target system has independent reset sources, such as voltage monitors, watchdog timers, power supply failures, or push-button switches, then the COP reset signals must be merged into these signals with logic.

The arrangement shown in [Figure 63](#) allows the COP port to independently assert $\overline{\text{HRESET}}$ or $\overline{\text{TRST}}$, while ensuring that the target can drive $\overline{\text{HRESET}}$ as well.

The COP interface has a standard header, shown in [Figure 62](#), for connection to the target system, and is based on the 0.025" square-post, 0.100" centered header assembly (often called a Berg header). The connector typically has pin 14 removed as a connector key.

The COP header adds many benefits such as breakpoints, watchpoints, register and memory examination/modification, and other standard debugger features. An inexpensive option can be to leave the COP header unpopulated until needed.

There is no standardized way to number the COP header; so emulator vendors have issued many different pin numbering schemes. Some COP headers are numbered top-to-bottom then left-to-right, while others use left-to-right then top-to-bottom. Still others number the pins counter-clockwise from pin 1 (as with an IC). Regardless of the numbering scheme, the signal placement recommended in [Figure 62](#) is common to all known emulators.

22.9.1 Termination of Unused Signals

Freescale recommends the following connections, when the JTAG interface and COP header are not used:

- $\overline{\text{TRST}}$ must be tied to $\overline{\text{HRESET}}$ through a 0 k Ω isolation resistor so that it is asserted when the system reset signal ($\overline{\text{HRESET}}$) is asserted, ensuring that the JTAG scan chain is initialized during the power-on reset flow. Freescale recommends that the COP header be designed into the system

24 Document Revision History

The following table provides a revision history for this hardware specification.

Table 88. Document Revision History

Rev. Number	Date	Substantive Change(s)
9	02/2012	<ul style="list-style-type: none"> Updated Section 21.2, "Thermal for Version 2.1.1, 2.1.2, and 2.1.3 Silicon FC-PBGA with Full Lid and Version 3.1.x Silicon with Stamped Lid," with version 3.0 silicon information. Added Figure 56, "Mechanical Dimensions and Bottom Surface Nomenclature of the FC-PBGA with Stamped Lid." Updated Table 87, "Part Numbering Nomenclature," with version 3.0 silicon information. Removed Note from Section 5.1, "Power-On Ramp Rate". Changed the Table 10 title to "Power Supply Ramp Rate". Removed table 11. Updated the title of Section 21.2, "Thermal for Version 2.1.1, 2.1.2, and 2.1.3 Silicon FC-PBGA with Full Lid and Version 3.1.x Silicon with Stamped Lid" to include Thermal Version 2.1.3 and Version 3.1.x Silicon. Corrected the leaded Solder Ball composition in Table 70, "Package Parameters" Updated Table 87, "Part Numbering Nomenclature," with Version 3.1.x silicon information. Updated the Min and Max value of TDO in the valid times row of Table 44, "JTAG AC Timing Specifications (Independent of SYSCLK)"¹ from 4 and 25 to 2 and 10 respectively .
8	04/2011	<ul style="list-style-type: none"> Added Section 14.1, "GPOUT/GPIN Electrical Characteristics." Updated Table 71, "MPC8548E Pinout Listing," Table 72, "MPC8547E Pinout Listing," Table 73, "MPC8545E Pinout Listing," and Table 74, "MPC8543E Pinout Listing," to reflect that the TDO signal is not driven during HRSET* assertion. Updated Table 87, "Part Numbering Nomenclature" with Ver. 2.1.3 silicon information.
7	09/2010	<ul style="list-style-type: none"> In Table 37, "MII Management AC Timing Specifications," modified the fifth row from "MDC to MDIO delay tMDKHDX (16 × tptb_clk × 8) – 3 — (16 × tptb_clk × 8) + 3" to "MDC to MDIO delay tMDKHDX (16 × tCCB × 8) – 3 — (16 × tCCB × 8) + 3." Updated Figure 55, "Mechanical Dimensions and Bottom Surface Nomenclature of the HiCTE FC-CBGA and FC-PBGA with Full Lid and figure notes.
6	12/2009	<ul style="list-style-type: none"> In Section 5.1, "Power-On Ramp Rate" added explanation that Power-On Ramp Rate is required to avoid falsely triggering ESD circuitry. In Table 13 changed required ramp rate from 545 V/s for MVREF and VDD/XVDD/SVDD to 3500 V/s for MVREF and 4000 V/s for VDD. In Table 13 deleted ramp rate requirement for XVDD/SVDD. In Table 13 footnote 1 changed voltage range of concern from 0–400 mV to 20–500mV. In Table 13 added footnote 2 explaining that VDD voltage ramp rate is intended to control ramp rate of AVDD pins.
5	10/2009	<ul style="list-style-type: none"> In Table 27, "GMII Receive AC Timing Specifications," changed duty cycle specification from 40/60 to 35/75 for RX_CLK duty cycle. Updated tMDKHDX in Table 37, "MII Management AC Timing Specifications." Added a reference to Revision 2.1.2. Updated Table 55, "MII Management AC Timing Specifications." Added Section 5.1, "Power-On Ramp Rate."